

**Search Notes**

Application/Control No.

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Examiner

Anthony Weier

Applicant(s)/Patent under  
Reexamination

EFSTATHIOU, JOHN D.

Art Unit

1761

**SEARCHED**

Class	Subclass	Date	Examiner
updated	previous search	5/10/2005	AW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR